



IAP01Rec'd PCT 25 NOV 2008

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of: **Kenji WATANABE et al.**

Art Unit: **2881**

Application Number: **10/543,151**

Examiner: **Kiet T. Nguyen**

Filed: **April 18, 2006**

Confirmation Number: **2634**

For: **MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS FOR  
INSPECTING SAMPLE BY USING ELECTRONS EMITTED FROM THE  
SAMPLE**

Attorney Docket Number: **052886**

Customer Number: **38834**

**AMENDMENT UNDER 37 C.F.R. § 1.111**

**Mail Stop Amendment**

Commissioner for Patents

P. O. Box 1450

Alexandria, VA 22313-1450

November 25, 2008

Sir:

This paper is filed in response to the Office Action dated August 25, 2008.

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 7 of this paper.

Form PCT/DO/EO/903 is attached following page 10 of this paper.